



# 測試報告

## Test Report

號碼(No.): ETR23405085

日期(Date): 02-May-2023

頁數(Page): 1 of 5

穩懋半導體股份有限公司 (WIN SEMICONDUCTORS CORP.)

桃園市龜山區華亞科技園區科技七路35號 (NO.35, KEJI 7TH RD., HWAYA TECHNOLOGY PARK, GUISHAN DISTRICT, TAOYUAN CITY 33383, TAIWAN)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by the applicant as) :

送樣廠商(Sample Submitted By) : 穩懋半導體股份有限公司 (WIN SEMICONDUCTORS CORP.)

樣品名稱(Sample Name) : pHEMT WAFER

收件日(Sample Receiving Date) : 21-Apr-2023

測試期間(Testing Period) : 21-Apr-2023 to 28-Apr-2023

測試需求(Test Requested) : 依據客戶要求進行測試，測試項目請參閱測試結果表格。(Testing item(s) is/are specified by client. Please refer to result table for testing item(s).)

測試結果(Test Results) : 請參閱下一頁 (Please refer to following pages.)

Troy Chang / Department Manager  
Signed for and on behalf of  
SGS TAIWAN LTD.  
Chemical Laboratory - Taipei



PIN CODE: 92883314

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## 測試部位敘述 (Test Part Description)

No.1 : 晶圓 (WAFER)

## 測試結果 (Test Results)

測試項目 (Test Items)	測試方法 (Method)	單位 (Unit)	MDL	結果 (Result)
				No.1
全氟辛烷磺酸及其鹽類 (PFOS and its salts) (CAS No.: 1763-23-1 and its salts)	參考CEN/TS 15968: 2010 · 以液相層析串聯質譜儀分析。(With reference to CEN/TS 15968: 2010, analysis was performed by LC/MS/MS.)	mg/kg	0.01	n.d.
全氟辛酸及其鹽類 (PFOA and its salts) (CAS No.: 335-67-1 and its salts)	參考CEN/TS 15968: 2010 · 以液相層析串聯質譜儀分析。(With reference to CEN/TS 15968: 2010, analysis was performed by LC/MS/MS.)	mg/kg	0.01	n.d.
鈹 (Be) (Beryllium (Be)) (CAS No.: 7440-41-7)	參考US EPA 3050B: 1996 · 以感應耦合電漿發射光譜儀分析。(With reference to US EPA 3050B: 1996, analysis was performed by ICP-OES.)	mg/kg	2	n.d.
銻 (Sb) (Antimony (Sb)) (CAS No.: 7440-36-0)	參考US EPA 3050B: 1996 · 以感應耦合電漿發射光譜儀分析。(With reference to US EPA 3050B: 1996, analysis was performed by ICP-OES.)	mg/kg	2	n.d.

## 備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 0.1% = 1000ppm
2. MDL = Method Detection Limit (方法偵測極限值)
3. n.d. = Not Detected (未檢出); 小於MDL / Less than MDL
4. 全氟辛烷磺酸及其鹽類包含等物質 (PFOS and its salts including) :  
CAS No.: 1763-23-1, 2795-39-3, 29457-72-5, 29081-56-9, 70225-14-8, 56773-42-3, 251099-16-8, 307-35-7, 91036-71-4, 4021-47-0 and others.
5. 全氟辛酸及其鹽類包含等物質 (PFOA and its salts including) :  
CAS No.: 335-67-1, 335-95-5, 2395-00-8, 335-93-3, 335-66-0, 3825-26-1 and others.

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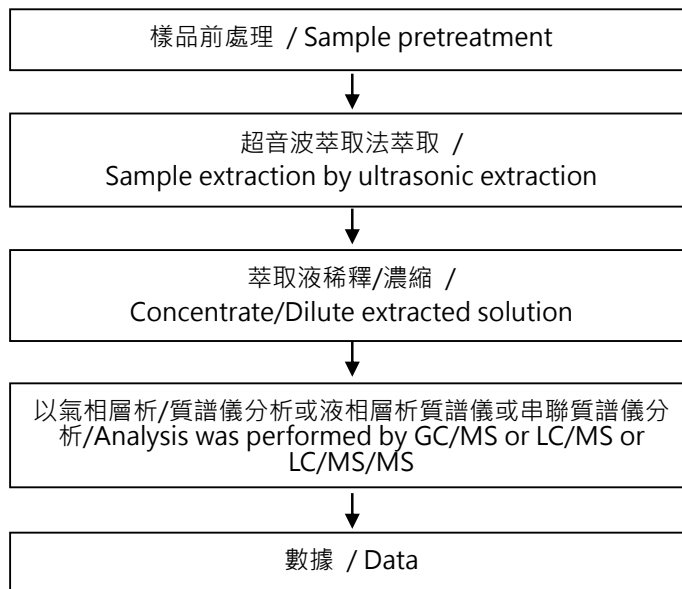
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### 全氟化合物(包含全氟辛酸/全氟辛烷磺酸/其相關化合物等等)分析流程圖 / Analytical flow chart – PFAS (including PFOA/PFOS/its related compound, etc.)



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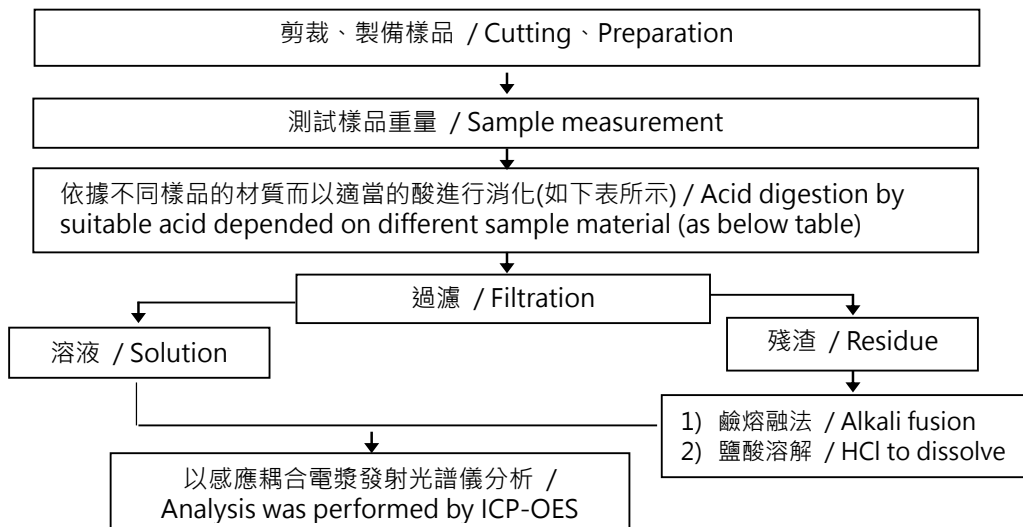
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### 元素以 ICP-OES 分析的消化流程圖

(Flow chart of digestion for the elements analysis performed by ICP-OES)

根據以下的流程圖之條件，樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.



鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氟酸,雙氧水 / Aqua regia, HNO <sub>3</sub> , HCl, HF, H <sub>2</sub> O <sub>2</sub>
玻璃 / Glass	硝酸,氫氟酸 / HNO <sub>3</sub> , HF
金,鉑,鈀,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO <sub>3</sub>
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / H <sub>2</sub> SO <sub>4</sub> , H <sub>2</sub> O <sub>2</sub> , HNO <sub>3</sub> , HCl
其他 / Others	加入適當的試劑至完全溶解 / Added appropriate reagent to total digestion

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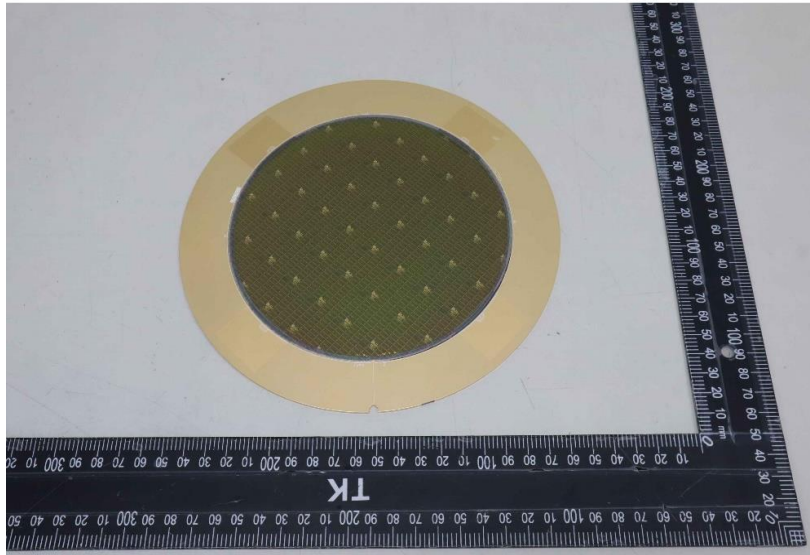
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\* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。\*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

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\*\* 報告結尾 (End of Report) \*\*

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